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CORRECTION

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Correction: Electrochemical gating enhances nearfield trapping of single metalloprotein junctions

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Correction for 'Electrochemical gating enhances nearfield trapping of single metalloprotein junctions' by Albert C. Aragonès *et al.*, *J. Mater. Chem. C*, 2021, DOI: 10.1039/d1tc01535d.

The authors regret an error in the *x*-axis scale of Fig. 2c in the published article (the value of 400 cm^{-1} should be replaced with 800 cm^{-1}). The corrected version of Fig. 2 is shown below (the caption remains unchanged). Please note that this error does not affect any of the discussions and conclusions reported in the article.

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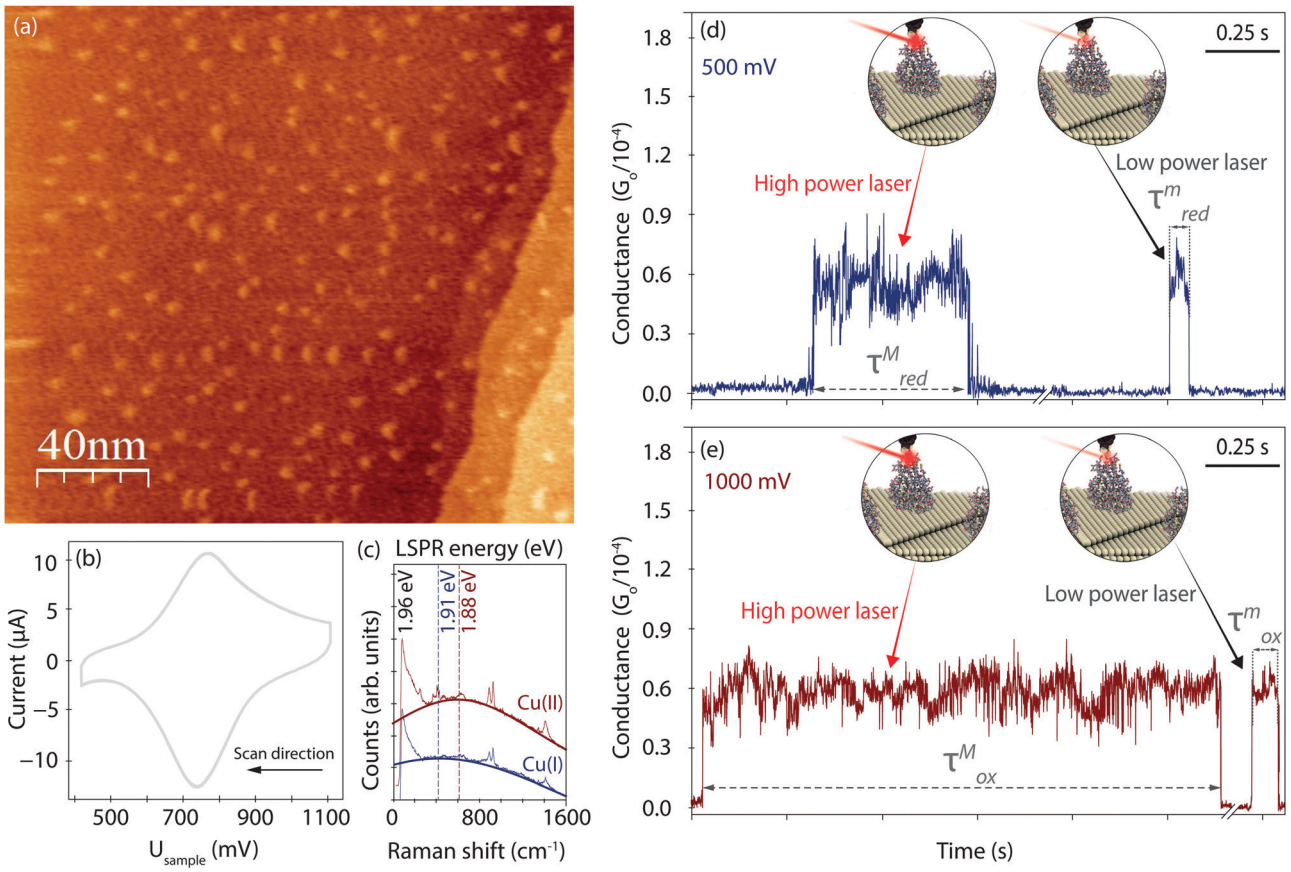

Fig. 2 (a) EC-STM image (200 nm × 200 nm, z-scale = 1 nm) of an Azu-functionalized Au(111) surface in 50 mM NH_4Ac buffer at pH 4.55 with U_{sample} = 1000 mV, U_{bias} = 300 mV, I_t = 1 nA. (b) CV of Azu under the conditions of (a) with a scan rate of 50 mV s^{-1}. (c) Raw TER spectra obtained with *ca.* 9.49 mW μm^{-2} farfield power density at 1.96 eV excitation energy and 120 s integration time of oxidized Cu(II) (U_{sample} = 1000 mV, red) and reduced Cu(I) (U_{sample} = 500 mV, blue) Azu, respectively. LSPR mode energies as extracted from Lorentzian fits to the TER spectral background are indicated with dotted vertical lines. (d and e) Examples of EC-PBJ captures of Azu junctions at (d) U_{sample} = 500 mV (blue, τ_{red}) and (e) U_{sample} = 1000 mV (red, τ_{ox}) with maximum (τ_M) and minimum (τ_m) laser power conditions of 9.49 mW μm^{-2} and 6.72 × 10^{-2} mW μm^{-2}, respectively.

The Royal Society of Chemistry apologises for these errors and any consequent inconvenience to authors and readers.